

Form PTO-1449 U.S. Department of Commerce
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.
036179/US/2-475387-30

Serial No.
10/577,562

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**
(Use several sheets if necessary)

Applicant(s)
Seok-Hyun Yun

Filing Date
April 27, 2006

Confirmation No.
3634

U.S. PATENT DOCUMENTS

*Exam. Init.	Document No.	Date	Name	Class	Subclass	Filing Date if Appropriate
	6 3 4 1 0 3 6	January 22, 2002	Tearney et al. ΩΩΩΩΩ			
	6 3 9 6 9 4 1	May 28, 2002	Bacus, James W. et al. ΩΩΩΩΩΩ			
200	5 0 1 8 2 0 1	January 27, 2005	De Boer, Johannes F. Et al ΩΩΩΩΩΩ			
	6 5 6 7 5 8 5	May 20, 2003	Martin et al ΩΩΩΩΩΩΩ			
	5 9 2 6 5 9 2	July 20, 1999	Martin et al. ΩΩΩΩΩΩΩ			
	7 2 6 7 4 9 4	September 11, 2007	Hongyu et al. ΩΩΩΩΩΩΩ			
	5 9 7 5 6 9 7	November 2, 1999	Podoleanu et al.			
	5 2 4 1 3 6 4	August 31, 1993	Kimura et al. ΩΩΩΩΩΩΩΩ Ω			
	5 9 1 0 8 3 9	June 8, 1999	Erschine et al ΩΩΩΩΩΩΩΩ Ω			
200	7 0 7 0 4 9 6	March 29, 2007	Gweon et al. ΩΩΩΩΩΩΩΩ Ω			
	4 8 2 7 9 0 7	May 9, 1989	Tashiro et al. ΩΩΩΩΩΩΩΩ ΩΩ			
	4 9 9 8 9 7 2	March 12, 1991	Chin et al. ΩΩΩΩΩΩΩΩ ΩΩ			
	5 7 3 0 7 3 1	March 24, 1998	Mollenauer et al. ΩΩΩΩΩΩΩΩ ΩΩ			
200	3 1 2 0 1 3 7	June 26, 2003	Pawluczyk et al ¥¥			

Examiner

Date Considered

* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. YY			
	2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. YYY			
	200	2	0	5	2	5	4	7	May 2, 2002	Toida Masahiro YYY			
	200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. YYY			
	200	3	0	8	2	1	0	5	May 1, 2003	Fischman, Alan et al. YYY			
		5	3	0	4	1	7	3	April 19, 1994	Kittrell, Carter et al. YYY			
		7	3	3	6	3	6	6	February 26, 2008	Choma et al.			
		7	0	1	9	8	3	8	March 28, 2006	Izatt et al.			
		6	3	7	4	1	2	8	April 16, 2002	Toida et al.			
		6	4	7	7	4	0	3	November 5, 2002	Eguchi et al.			
		5	5	5	5	0	8	7	September 10, 1996	Miyagawa et al. YYYY			
	200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. YYYY			
	200	5	0	3	5	2	9	5	February 17, 2005	Bouma et al.			
	200	3	0	2	8	1	1	4	February 6, 2003	Casscells, III et al.			
	200	3	0	9	7	0	4	8	May 22, 2003	Ryan et al.			

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	200	4	0	5	4	2	6	8	March 18, 2004	Esenaliev et al.			
	200	4	0	7	7	9	4	9	April 22, 2004	Blofgett et al.			
	200	4	0	7	2	2	0	0	April 15, 2004	Rigler et al.			
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		Document No.							Date	Country	Class	SubClass	Translator	
													Yes	No
	200	2	0	8	4	2	6	3	October 24, 2002	WIPO ΩΩΩΩΩ				
	200	4	0	5	7	2	6	6	July 8, 2004	WIPO ΩΩΩΩΩ				
	200	1	0	2	7	6	7	9	April 19, 2001	WIPO ΩΩΩΩΩ				
	200	3	0	4	6	6	3	6	June 5, 2003	WIPO ΩΩΩΩΩ				
	200	6	0	0	4	7	4	3	January 12, 2006	WIPOΩΩΩΩ ΩΩΩΩ				
		9	2	0	1	9	6	6	February 6, 1992	WIPO¥				
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		5	5	0	9	4	1	7	November 22, 1993	Japan¥				
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ΩΩΩΩΩΩΩReference cited in Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483

¥Reference cited in Japanese Office Action dated December 2, 2008

¥¥Reference cited in International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447

¥¥¥Reference cited in European Official Communication dated February 12, 2008 for EP 07718117.0

¥¥¥¥Reference cited in International Search Report and Written Opinion dated June 10, 2009 for PCT/US2008/075456

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			Copy of International Search Report and Written Opinion dated December 20, 2004 for PCT/US04/10152
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		Copy of Notification Concerning Transmittal of Copy of International Preliminary Report on Patentability dated October 13, 2005 for PCT/US04/10152
		Copy of International Search Report and Written Opinion dated March 23, 2006 for PCT/US2005/042408
		Copy of International Preliminary Report on Patentability dated June 7, 2007 for PCT/US2005/042408
		Copy of International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277 ΩΩΩΩΩΩ
		Copy of International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834ΩΩΩΩΩΩΩΩ
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		Bilenca A et al: "The Role of Amplitude and phase in Fluorescence Coherence Imaging: From Wide Filed to Nanometer Depth Profiling", <i>Optics IEEE</i> , May 5, 2007 ΩΩΩΩΩΩΩΩ
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		Bernet, S et al: "Quantitative Imaging of Complex Samples by Spiral Phase Contrast Microscopy", <i>Optics Express</i> , May 9, 2006 ΩΩΩΩΩΩΩΩ
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		Copy of Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483
		Copy of Notice of Reasons for Rejection mailed December 2, 2008 for Japanese patent application no. 2000-533782

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			Copy of International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447
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			Barfuss et al (1989) "Modified Optical Frequency Domain Reflectometry with High spatial Resolution for Components of integrated optic Systems", Journal of Lightwave Technology, IEEE Vol 7., No. 1
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			Gelikono, V.M. et al. October 1, 2004 "Two-Wavelength Optical Coherence Tomography" Radio Physics and Quantum Electronics, Kluwer Academic Publishers-Consultants, Vol. 47, No. 10-1

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